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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/674,444	10/31/2000	Symon Reuben Brewer	20251-000100 9030		
7590 10/28/2005 Townsend And Townsend And Crew			EXAMINER FILE, ERIN M		
Donver, CC C	0202 3027		2634	2634	
			DATE MAILED: 10/28/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

		Applicati	on No.	Applicant(s)				
			44	BREWER, SYMON REUBEN				
Office Action Summary		Examine	r	Art Unit				
		Erin M. F	le	2634				
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply								
A SHOWHIC - Exter after - If NO - Failu Any r	ORTENED STATUTORY PERIOD FOR FOR HEVER IS LONGER, FROM THE MAILIN asions of time may be available under the provisions of 37 CSIX (6) MONTHS from the mailing date of this communication period for reply is specified above, the maximum statutory to to reply within the set or extended period for reply will, by reply received by the Office later than three months after the red patent term adjustment. See 37 CFR 1.704(b).	NG DATE OF TI CFR 1.136(a). In no ex ion. period will apply and w v statute, cause the app	HIS COMMUNICATION rent, however, may a reply be tim rill expire SIX (6) MONTHS from blication to become ABANDONEI	. lely filed the mailing date of this co D (35 U.S.C. § 133)	• ,			
Status								
1)⊠	Responsive to communication(s) filed on	29 June 2005.						
2a)	This action is FINAL . 2b)⊠ This action is non-final.							
3)	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is							
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.								
Dispositi	on of Claims							
5)□ 6)⊠ 7)□	Claim(s) 1-3,5-12 and 15-23 is/are pendid 4a) Of the above claim(s) is/are wid Claim(s) is/are allowed. Claim(s) 1-3,5-12 and 15-23 is/are rejected Claim(s) is/are objected to. Claim(s) are subject to restriction is	thdrawn from co	nsideration.					
Applicati	on Papers							
10) 🖾	The specification is objected to by the Example The drawing(s) filed on 31 October 2000 is Applicant may not request that any objection is Replacement drawing sheet(s) including the of the oath or declaration is objected to by the	is/are: a)⊠ acc to the drawing(s) correction is requi	be held in abeyance. See red if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 Cf	FR 1.121(d).			
Priority u	ınder 35 U.S.C. § 119							
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 								
2) Notic	t(s) e of References Cited (PTO-892) e of Draftsperson's Patent Drawing Review (PTO-94 nation Disclosure Statement(s) (PTO-1449 or PTO/	•	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P	ite	O-152)			
	r No(s)/Mail Date		6) Other:	•	•			

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DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1, 2, 5-11, 15-17, 19-23 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shohet and in view of Lee.

Claims 1, 10, 11, Shohet discloses forming an offset reference clock signal being offset by a predetermined frequency amount from said digital signal; (column 4, lines 50-65, fig 1., fig 2) and sampling said digital signal at sampling times determined by an integer multiple of the frequency of said offset reference clock signal, such that, in the absence of jitter and said offset by a predetermined frequency, there are a predetermined number of sampling times in each bit of said digital signal; (column 4, lines 50-65), fig 1., fig 2 detecting occasions when the number of sampling times in any bit of said digital signal is different from said predetermined number; Abstract counting said occasions over a predetermined time, and fig 1, Abstract deriving at least one measure of jitter from said counting of said occasions (Column 3, Lines 50-54). Shohet fails to disclose

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the offset reference clock signal moving relative to a transition point for bits of the digital signal. However, Lee discloses the creation of an output pulse train responding to transitions in the received digital data signal (col. 2, lines 46-48). Because Lee discloses that the creation of this pulse train is for synchronization purposes, which improve the ability make accurate measurements, it would be obvious to one skilled in the art at the time of invention to incorporate Lee's disclosure into Shohet's jitter measurement device.

Claims 2, 17, Shohet discloses wherein said offset reference clock signal is formed by extracting a clock signal from said digital signal and offsetting said clock signal by said predetermined frequency (Column 1, lines 39-44).

Claim 5, 16, 20, Sohet discloses sampling the times are at clock bit intervals being plus and minus one of said integer multiple (Fig. 2)

Claims 6, 15, 19, contain the limitations of Claim 1, although both Lee and Shohet fail to disclose the method of determining a sampling period, using the inverse proportion of the bit rate and higher frequency offset is a design choice and simply represents using the original clock frequency (bit rate) and some offset.

Claims 7, 21, Shohet meets the following limitations of the Claim: wherein one of said at least one measure of jitter is obtained by counting up one value for each of said

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occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and determining the difference between the maximum count value and the minimum count value. Abstract; (Column 3, lines S6-65)

Claims 8, 22, Shohet meets the following limitations of the Claim: wherein one of said at least one measure of jitter is obtained by counting up one value for each of said occasions representing sampling times greater than the predetermined number within a bit, counting down one value for each of said occasions representing sampling times less than the predetermined number within a bit and determining the time difference between the first occasion of the maximum count value and the last occasion of the minimum count value. Abstract; (Column 3, lines 56-60)

Claims 9, 23, Shohet meets the following limitations of the Claim: wherein the time difference is divided by said integer multiple and said predetermined time. fig 2: fig 1, item 22, 24: (Column 4, Lines 11-12)

3. Claims 3, 12, and 18 are rejected under 35 U.S.C. 103(a) as being unpatentable over Shohet and Lee and in further view of Yoshimura et al.

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in to the combined invention of Shohet and Lee.

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Claims 3, 12, 18, inherit the limitations of Claims 1, 11, and 17 respectively. Both Shohet and Lee fail to smoothing of the reference clock. However, Yoshimura discloses "a phase comparator (5) for calculating a phase difference by using sampled values before and after an edge portion of the signals outputted from the A/D converter (4), a filter (6) for smoothing the phase difference outputted from the phase comparator (5) so as to output a signal converted into a direct current, a variable frequency oscillator (7) for reproducing a synchronous clock on the basis of the signal-outputted from the filter (6), a jitter measuring section 9 for detecting a jitter detection signal on the basis of unevenness of the phase difference obtained by the phase comparator (5)" (col. 3, lines 12-24). Because smoothing the reference clock can result in more accurate phase measurements, resulting in improved jitter measurement, it would be obvious to one skilled in the art at the time of invention to incorporate the clock smoothing of Toshimura

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4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Erin M. File whose telephone number is (571)272-6040. The examiner can normally be reached on M-F 9:30-6:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Stephen Chin can be reached on (571)272-3056. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Erin M. File

10/21/2005

STEPHEN CHIN
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